

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7MH273FK

## Octal D-Type Flip Flop with Clear

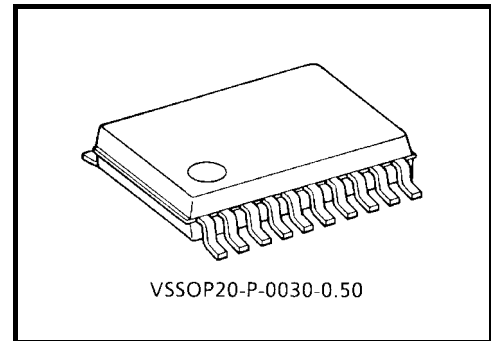
The TC7MH273FK is an advanced high speed CMOS octal D-type flip-flop fabricated with silicon gate C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent bipolar schottky TTL while maintaining the CMOS low power dissipation.

Information signals applied to D inputs are transferred to the Q outputs on the positive going edge of the clock pulse.

When the CLR input is held "L", the Q outputs are at a low logic level independent of the other inputs.

An input protection circuit ensures that 0 to 5.5 V can be applied to the input pins without regard to the supply voltage. This device can be used to interface 5 V to 3 V systems and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

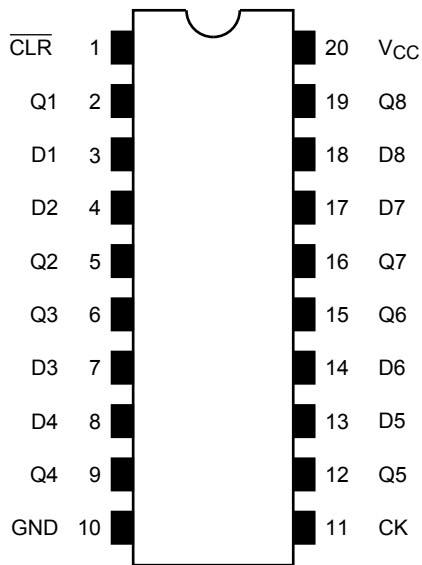


Weight: 0.03 g (typ.)

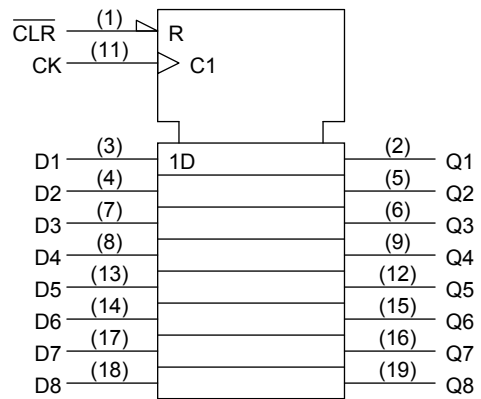
## Features

- High speed:  $f_{\max} = 165 \text{ MHz (typ.) (} V_{CC} = 5 \text{ V)}$
- Low power dissipation:  $I_{CC} = 4 \mu\text{A (max) (} T_a = 25^\circ\text{C)}$
- High noise immunity:  $V_{NIH} = V_{NIL} = 28\% V_{CC} \text{ (min)}$
- Power down protection is provided on all inputs.
- Balanced propagation delays:  $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range:  $V_{CC} \text{ (opr)} = 2\sim 5.5 \text{ V}$
- Low noise:  $V_{OLP} = 0.8 \text{ V (max)}$
- Pin and function compatible with 74ALS273

## Pin Assignment (top view)



## IEC Logic Symbol

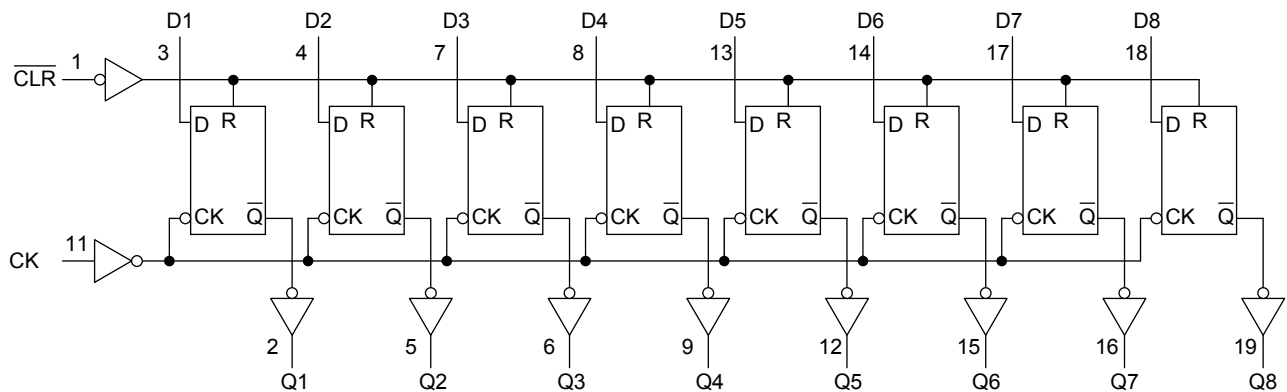


## Truth Table

Inputs			Outputs	Function
$\overline{\text{CLR}}$	D	CK	Q	
L	X	X	L	Clear
H	L	$\uparrow$	L	—
H	H	$\uparrow$	H	—
H	X	$\downarrow$	$Q_n$	No change

X: Don't care

## System Diagram



## Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage range	$V_{CC}$	-0.5~7.0	V
DC input voltage	$V_{IN}$	-0.5~7.0	V
DC output voltage	$V_{OUT}$	-0.5~ $V_{CC} + 0.5$	V
Input diode current	$I_{IK}$	-20	mA
Output diode current	$I_{OK}$	±20	mA
DC output current	$I_{OUT}$	±25	mA
DC $V_{CC}$ /ground current	$I_{CC}$	±75	mA
Power dissipation	$P_D$	180	mW
Storage temperature	$T_{stg}$	-65~150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	$V_{CC}$	2.0~5.5	V
Input voltage	$V_{IN}$	0~5.5	V
Output voltage	$V_{OUT}$	0~ $V_{CC}$	V
Operating temperature	$T_{opr}$	-40~85	°C
Input rise and fall time	dt/dv	0~100 ( $V_{CC} = 3.3 \pm 0.3$ V)	ns/V
		0~20 ( $V_{CC} = 5 \pm 0.5$ V)	

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{CC}$  or GND.

## Electrical Characteristics

### DC Characteristics

Characteristics		Symbol	Test Condition	$T_a = 25^\circ\text{C}$			$T_a = -40\sim 85^\circ\text{C}$		Unit		
				$V_{CC}$ (V)	Min	Typ.	Max	Min		Max	
Input voltage	"H" level	$V_{IH}$	—	2.0	1.50	—	—	1.50	V		
				3.0~5.5	$V_{CC} \times 0.7$	—	—	$V_{CC} \times 0.7$		—	
	"L" level	$V_{IL}$		2.0	—	—	0.50	—		0.50	
				3.0~5.5	—	—	$V_{CC} \times 0.3$	—		$V_{CC} \times 0.3$	
Output voltage	"H" level	$V_{OH}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OH} = -50 \mu\text{A}$	2.0	1.9	2.0	—	1.9	V	
					3.0	2.9	3.0	—	2.9		—
				$I_{OH} = -4 \text{ mA}$	3.0	2.58	—	—	2.48		—
					4.5	3.94	—	—	3.80		—
	"L" level	$V_{OL}$		$I_{OL} = 50 \mu\text{A}$	2.0	—	0	0.1	—		0.1
					3.0	—	0	0.1	—		0.1
				$I_{OL} = 4 \text{ mA}$	4.5	—	0	0.1	—		0.1
					4.5	—	—	0.36	—		0.44
				$I_{OL} = 8 \text{ mA}$	3.0	—	—	0.36	—	0.44	
					4.5	—	—	0.36	—	0.44	
Input leakage current		$I_{IN}$	$V_{IN} = 5.5 \text{ V}$ or GND	0~5.5	—	—	±0.1	—	±1.0	μA	
Quiescent supply current		$I_{CC}$	$V_{IN} = V_{CC}$ or GND	5.5	—	—	4.0	—	40.0	μA	

## Timing Requirements (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition	Ta = 25°C		Ta = -40~85°C		Unit
			VCC (V)	Typ.	Limit	Limit	
Minimum pulse width (CK)	$t_w(L)$ $t_w(H)$	—	3.3 ± 0.3	—	5.5	6.5	ns
			5.0 ± 0.5	—	5.0	5.0	
Minimum pulse width ( $\overline{\text{CLR}}$ )	$t_w(L)$	—	3.3 ± 0.3	—	5.0	6.0	ns
			5.0 ± 0.5	—	5.0	5.0	
Minimum set-up time	$t_s$	—	3.3 ± 0.3	—	5.5	6.5	ns
			5.0 ± 0.5	—	4.5	4.5	
Minimum hold time	$t_h$	—	3.3 ± 0.3	—	1.0	1.0	ns
			5.0 ± 0.5	—	1.0	1.0	
Minimum removal time ( $\overline{\text{CLR}}$ )	$t_{rem}$	—	3.3 ± 0.3	—	2.5	2.5	ns
			5.0 ± 0.5	—	2.0	2.0	

## AC Characteristics (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition			Ta = 25°C			Ta = -40~85°C		Unit	
			VCC (V)	CL (pF)	Min	Typ.	Max	Min	Max		
Propagation delay time (CK-Q)	$t_{pLH}$ $t_{pHL}$	—	3.3 ± 0.3	15	—	8.7	13.6	1.0	16.0	ns	
				50	—	11.2	17.1	1.0	19.5		
			5.0 ± 0.5	15	—	5.8	9.0	1.0	10.5		ns
				50	—	7.3	11.0	1.0	12.5		
Propagation delay time ( $\overline{\text{CLR}}-Q$ )	$t_{pHL}$	—	3.3 ± 0.3	15	—	8.9	13.6	1.0	16.0	ns	
				50	—	11.4	17.1	1.0	19.5		
			5.0 ± 0.5	15	—	5.2	8.5	1.0	10.0		ns
				50	—	6.7	10.5	1.0	12.0		
Maximum clock frequency	$f_{max}$	—	3.3 ± 0.3	15	75	120	—	65	—	MHz	
				50	50	75	—	45	—		
			5.0 ± 0.5	15	120	165	—	100	—		MHz
				50	80	110	—	70	—		
Output to output skew	$t_{osLH}$ $t_{osHL}$	(Note 1)	3.3 ± 0.3	50	—	—	1.5	—	1.5	ns	
			5.0 ± 0.5	50	—	—	1.0	—	1.0		
Input capacitance	$C_{IN}$	—	—	—	4	10	—	10	pF		
Power dissipation capacitance	$C_{PD}$	(Note 2)	—	—	31	—	—	—	pF		

Note 1: This parameter is guaranteed by design.

$$t_{osLH} = |t_{pLHm} - t_{pLHn}|, t_{osHL} = |t_{pHLm} - t_{pHLn}|$$

Note 2:  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC(opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 \text{ (per F/F)}$$

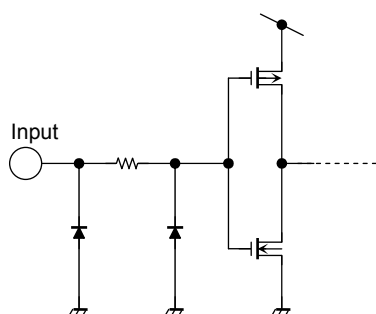
And the total  $C_{PD}$  when n pcs of flip-flop operate can be gained by the following equation:

$$C_{PD}(\text{total}) = 22 + 9 \cdot n$$

## Noise Characteristics (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition	Ta = 25°C			Unit
			V <sub>CC</sub> (V)	Typ.	Limit	
Quiet output maximum dynamic V <sub>OL</sub>	V <sub>OLP</sub>	C <sub>L</sub> = 50 pF	5.0	0.5	0.8	V
Quiet output minimum dynamic V <sub>OL</sub>	V <sub>OLV</sub>	C <sub>L</sub> = 50 pF	5.0	-0.5	-0.8	V
Minimum high level dynamic input voltage V <sub>IH</sub>	V <sub>IHD</sub>	C <sub>L</sub> = 50 pF	5.0	—	3.5	V
Maximum low level dynamic input voltage V <sub>IL</sub>	V <sub>ILD</sub>	C <sub>L</sub> = 50 pF	5.0	—	1.5	V

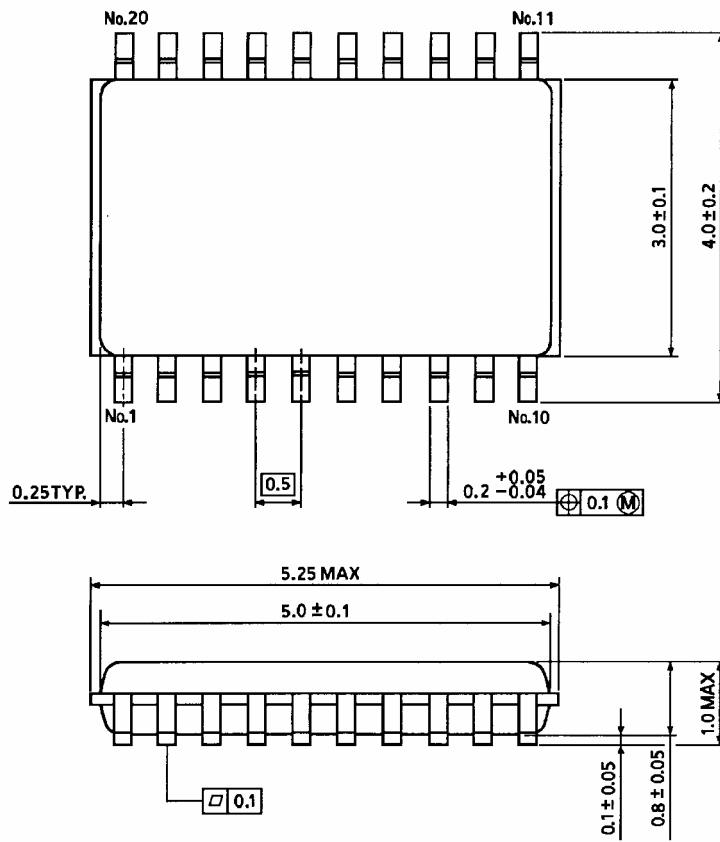
## Input Equivalent Circuit



## Package Dimensions

VSSOP20-P-0030-0.50

Unit : mm



Weight: 0.03 g (typ.)

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20070701-EN GENERAL

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